

**AMENDMENTS TO THE CLAIMS**

1. (Currently Amended) A method of determining an appropriate refresh interval for a DRAM chip, the method comprising:

detecting device startup;

providing a clock pulse as a refresh interval;

~~self-testing a plurality of memory cells using the refresh interval;~~

writing an original test code to a plurality of memory cells;

refreshing the memory cells a plurality of times by using the refresh interval;

comparing saved test code with the original test code, to determine an effectiveness of the refresh interval;

modifying the refresh interval and repeating the above steps;

determining ~~[[the]]~~ a longest refresh interval as a result of the self-testing procedure; and

using the appropriate refresh interval, defined by the longest refresh interval, to refresh the DRAM.

2. (Currently Amended) The method of determining the appropriate refresh interval as claimed in claim 1, further comprising:

outputting a self-test success signal when the result of the comparison is equal; and

outputting a self-test failure signal when the result of the comparison is unequal. wherein

~~the self testing further comprises:~~

~~writing an original test code to a plurality of DRAM memory cells;~~

~~refresh the DRAM memory cells several times by using the refresh clock;~~

~~comparing saved test code with the original test code, to determine the effectiveness of the refresh interval;~~

~~if the result of the comparison is equal, the system outputs a self test success signal; and~~

~~if the result of the comparison is unequal, the system outputs a self test failure signal.~~

3. (Currently Amended) The method of finding the appropriate refresh interval as claimed in claim 1, wherein ~~the~~ a definition of the most appropriate refresh interval comprises:

the most appropriate refresh interval is the longest refresh interval plus a specific variable.